# Multiwavelength anomalous diffraction at high x-ray intensity

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**Center for Free-Electron Laser Science** 

CFEL is a scientific cooperation of the three organizations: DESY – Max Planck Society – University of Hamburg

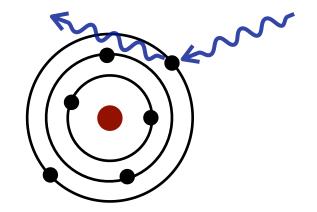




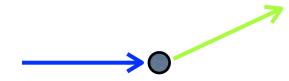
### X-ray scattering

> Elastic x-ray scattering form factor

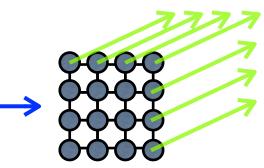
$$\begin{split} f^{0}(\mathbf{Q}) &= \int d^{3}r \ \rho(\mathbf{r}) \ e^{i\mathbf{Q}\cdot\mathbf{r}} \\ \frac{d\sigma(\mathbf{Q})}{d\Omega} &= \left(\frac{d\sigma}{d\Omega}\right)_{T} \left|f^{0}(\mathbf{Q})\right|^{2} \end{split}$$



Carbon at synchrotron radiation: 12 keV, 10<sup>6</sup> photons on 10µm × 10µm



scattering probability ~ 10<sup>-12</sup>



 ~10<sup>8</sup> molecules in a crystal: diffraction patterns
→ X-ray crystallography





# **Bottlenecks in X-ray crystallography**

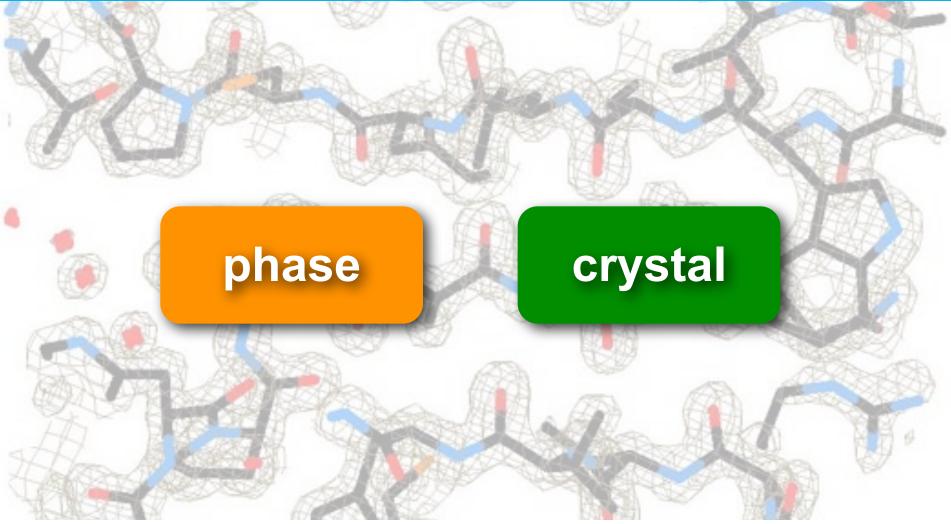


Figure taken from <a href="http://www.jic.ac.uk/staff/david-lawson/xtallog/summary.htm">http://www.jic.ac.uk/staff/david-lawson/xtallog/summary.htm</a>





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#### **Phase problem**

> Phase problem: a fundamental obstacle in constructing an electronic density map from x-ray diffraction

$$f^{0}(\mathbf{Q}) = \int d^{3}r \ \rho(\mathbf{r}) \ e^{i\mathbf{Q}\cdot\mathbf{r}} = |f^{0}(\mathbf{Q})| \ e^{i\phi^{0}(\mathbf{Q})}$$

- > Phases are essential for structural determination, but they are lost in measurement.
- > Phasing method: how to recover phases
- MAD (Multiwavelength Anomalous Diffraction) is one of the most powerful phasing methods.



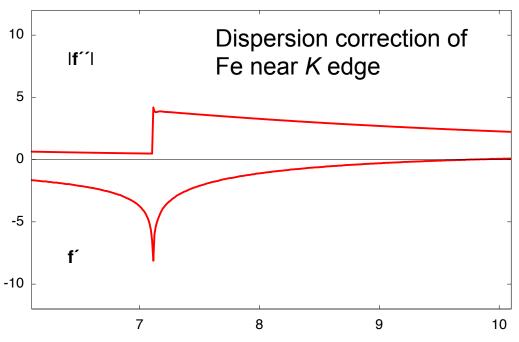


# **Multiwavelength Anomalous Diffraction**

> Dispersion correction:  $f(\mathbf{Q}, \omega) = f^0(\mathbf{Q}) + f'(\omega) + if''(\omega)$ 

MAD phasing: The Karle-Hendrickson equation provides a simple way for phasing from the contrast at two or more wavelengths.

Karle, *Int. J. Quant. Chem.* **18**, Suppl. S7, 357 (1980). Hendrickson, *Trans. Am. Crystalgr. Assoc.* **21**, 11 (1985).



Photon energy (keV)

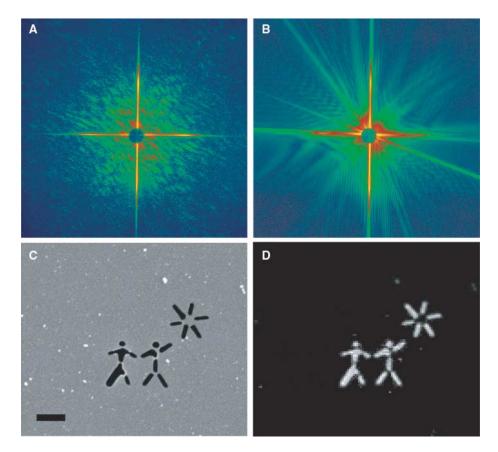
The MAD method has been a well-established phasing method with synchrotron radiation sources since late 80's: Science 241, 806 (1998); PNAS 86, 2190 (1989); Science 249, 1398 (1990); Science 254, 51 (1991).





# X-ray free-electron laser

- Srowing high-quality crystals is one of major bottlenecks in x-ray crystallography.
- > Unprecedented high x-ray fluence from XFEL (×10<sup>6</sup> larger than synchrotron radiation)
- Enough signals from nano-sized crystals and single molecules
- Single-shot molecular imaging: revolutionary impact on structural biology



Chapman *et al.*, *Nature Phys.* **2**, 839 (2006). Figure taken from Gaffney & Chapman, *Science* **316**, 1444 (2007).

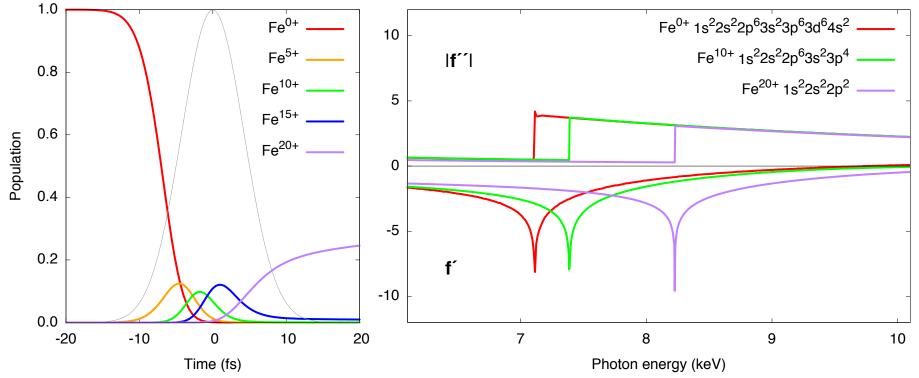




## **Electronic damage to heavy atoms**

Population dynamics of Fe charge states during an XFEL pulse (8 keV,  $5 \times 10^{12}$  photons/µm<sup>2</sup>, 10 fs FWHM)

Dispersion corrections of atomic form factors of Fe and its ions



Adapted from Son, Chapman & Santra, PRL 107, 218102 (2011).



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# **Prior speculations regarding MAD at XFEL**

- > Unavoidable electronic damage, esp. to heavy atoms
- > Dramatic change of anomalous scattering for high charge states
- Stochastic electronic damage to heavy atoms would destroy coherent scattering signals in nanocrystals
- > MAD would not be an applicable route for phasing at XFEL...?

- > We demonstrate the existence of a Karle-Hendrickson-type equation in the high-intensity regime.
- We show that MAD not only works, but also the extensive electronic rearrangements at high x-ray intensity provide a new path to phasing.

Son, Chapman & Santra, PRL 107, 218102 (2011).





# Scattering intensity including elec. damage

$$\frac{dI(\mathbf{Q},\omega)}{d\Omega} = \mathcal{F}C(\Omega) \int_{-\infty}^{\infty} dt \, g(t) \sum_{I} P_{I}(t) \left| F_{P}^{0}(\mathbf{Q}) + \sum_{j=1}^{N_{H}} f_{I_{j}}(\mathbf{Q},\omega) e^{i\mathbf{Q}\cdot\mathbf{R}_{j}} \right|^{2}$$

$$I = (I_1, I_2, \cdots I_{N_H}), \quad P_I(t) = \prod_{j=1}^{N_H} P_{I_j}(t)$$
$$f_{I_j}(\mathbf{Q}, \omega) = f_{I_j}^0(\mathbf{Q}) + f'_{I_j}(\omega) + i f''_{I_j}(\omega)$$

- P: protein, H: heavy atoms; only heavy atoms scatter anomalously and undergo damage dynamics during an x-ray pulse.
- > All changes among  $N_H$  heavy atoms are included.
- Heavy atoms are ionized independently.
- > Only one species of heavy atoms is considered.

Son, Chapman & Santra, *PRL* **107**, 218102 (2011).





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### **Generalized Karle-Hendrickson equation**

$$\frac{dI(\mathbf{Q},\omega)}{d\Omega} = \mathcal{F}C(\Omega) \Big[ |F_P^0(\mathbf{Q})|^2 + |F_H^0(\mathbf{Q})|^2 \tilde{a}(\mathbf{Q},\omega) + |F_P^0(\mathbf{Q})| |F_H^0(\mathbf{Q})| b(\mathbf{Q},\omega) \cos \Delta \phi^0(\mathbf{Q}) + |F_P^0(\mathbf{Q})| |F_H^0(\mathbf{Q})| c(\mathbf{Q},\omega) \sin \Delta \phi^0(\mathbf{Q}) + N_H |f_H^0(\mathbf{Q})|^2 \{a(\mathbf{Q},\omega) - \tilde{a}(\mathbf{Q},\omega)\} \Big]$$

- > MAD coefficients:  $a(\mathbf{Q}, \omega), b(\mathbf{Q}, \omega), c(\mathbf{Q}, \omega), \text{ and } \tilde{a}(\mathbf{Q}, \omega)$ 
  - $\rightarrow$  measured or calculated with time evolution of config. populations
- > 3 unknowns:  $|F_P^0(\mathbf{Q})|, |F_H^0(\mathbf{Q})|, \Delta \phi^0(\mathbf{Q}) [= \phi_P^0(\mathbf{Q}) \phi_H^0(\mathbf{Q})]$ 
  - $\rightarrow$  solvable with measurements at 3 different wavelengths.

Son, Chapman & Santra, PRL 107, 218102 (2011).





# **XATOM: x-ray and atomic physics toolkit**

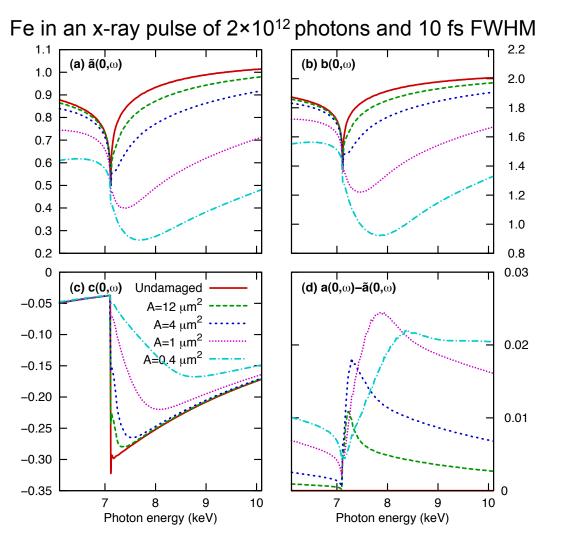
#### X-ray-induced atomic processes for any given element and configuration

- photoionization cross section
- Auger / Coster-Kronig decay rate
- fluorescence rate
- coherent x-ray scattering form factor and dispersion correction
- shake-off branching ratio
- Rate equation model to simulate ionization and relaxation dynamics
- > Applications
  - Nonlinear x-ray absorption processes; PRL 106, 083002 (2011); PRA 85, 023414 (2011)
  - Charge distribution analysis of noble gases in XFELs; Rudek et al., submitted
  - Photoelectron / Auger / fluorescence spectra; Son & Santra, in preparation
  - Scattering with electronic damage dynamics at high intensity; *PRA* 83, 033402 (2011)
  - Multi-wavelength anomalous diffraction at high intensity; *PRL* **107**, 218102 (2011)





### **MAD coefficients**

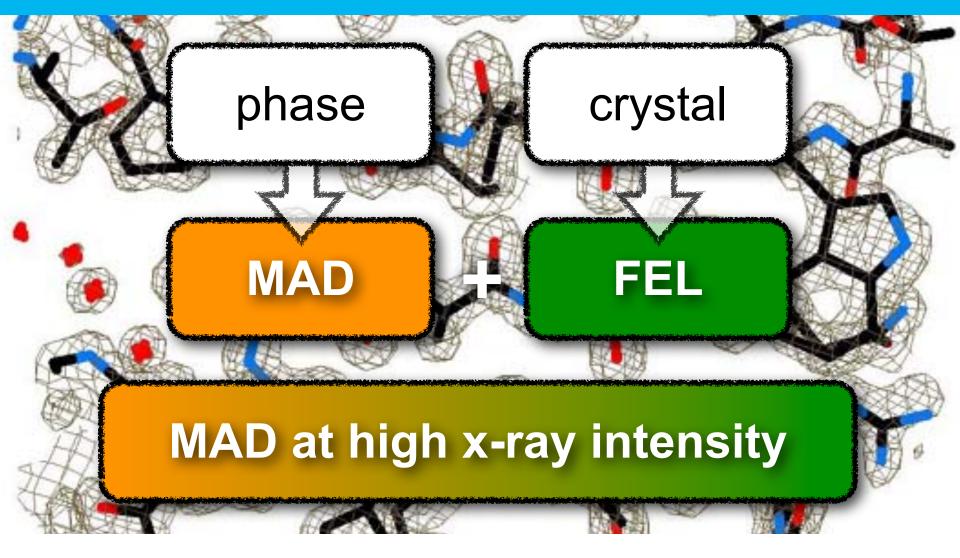


- calculated by XATOM
- bleaching effect: minimum deepened and edge broadened
- MAD works: enhanced contrast at different wavelengths
  - > alternative phasing method similar to SIR (single isomorphic replacement) or RIP (radiation-damage induced phasing)

Son, Chapman & Santra, *PRL* **107**, 218102 (2011).











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#### Acknowledgment

#### **CFEL Theory Division**



Thank you for your attention!



